

Notice of References Cited

Application/Control No.

10/508,846

Applicant(s)/Patent Under
Reexamination
TOMOE ET AL.

Examiner

Eric B. Kiss

Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0133794 A1	09-2002	Kanapathippillai et al.	716/4
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Product Bulletin: Boundary-Scan Logic," 1998, Texas Instruments, pp. 1-8.
	V	"Topic 8 - JTAG Boundary Scan," 1997, 1997 TI Test Symposium, 7 pages.
	W	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.